


<b>Search Notes</b>  	<b>Application/Control No.</b>  10710855	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG, SUNG-SAN
	<b>Examiner</b>  Heyi, Henok G	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner
720	601	06/21/2007	Henok heyi
	602	06/21/2007	Henok heyi

SEARCH NOTES		
Search Notes	Date	Examiner
Conducted both classified and text search using EAST. I have also used google patents. I got help in search, claim interpretation and analysis from the class assistant trainer, Krista. I also asked a primary examiner, Tan Dinh, to direct me to the right classification of this application because it was not properly classified.	06/21/2007	Henok Heyi

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner